Amendments to the Claims:

This listing of claims will replace all prior versions, and listings of claims in the application:

Listing of Claims:

1. (currently amended) A method for repairing line pattern defects in a flat panel display having a branch of at least a scan line or a signal line at an intersectional region between the scan line and the signal line, the method comprising:

detecting a shorting defect between a scan line and signal line <u>disposed with</u> an interlayer insulation film therebetween and identifying the location of the <u>shorting</u> defect in a flat panel display unit wherein the scan lines or signal lines or both scan lines and signal lines branch in two parts at an intersection between scan lines an signal lines, disposed with an interlayer insulation film therebetween;

forming an <u>organic</u> insulating layer to cover [[a]] <u>the intersectional</u> region at the <u>location of the with a shorting defect locally, then; and</u>

cutting the <u>branch at two regions as to sandwich</u> portion-containing the <u>intersection between the sean line and signal line where</u> the shorting defect is located with <u>using</u> a laser beam <u>before curing the organic insulation film.</u>; and

forming an insulation film locally at the cut to repair the shorting defect.

- 2. (original) A method for repairing line defects as described in claim 1, wherein the flat panel display unit is a liquid crystal display panel.
- 3. (currently amended) A method for repairing line defects as described in claim 1, wherein the <u>organic</u> insulation film is formed locally at the cut part of locally supplying an insulation film material to the cut and heat curing the locally supplied insulation film material includes a material selected from the group consisting of silicon oxide resin, polyimide resin, epoxy resin, and acrylic resin.
- 4. (previously presented) A method for repairing line defects in a flat panel display having a branch of a scan line at an intersectional region between the scan line and a signal line, the method comprising:

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detecting a shorting defect between a scan line and <u>the</u> signal line <u>disposed</u> in a flat panel display unit wherein scan lines and signal lines are formed with an interlayer insulation film therebetween;

storing the position of the detected shorting defect;

forming supplying an organic insulating layer material to cover a region at the location of the intersectional region with a shorting defect locally, then;

severing the scan line at two regions near the stored position of the shorting defect with a laser beam near the stored position of the shorting defect before curing the organic insulation material; supplying an insulation film material locally to the area containing the severed part of the scan line; and

curing the supplied forming an organic insulation film material on to the repaired portion.

- 5. (canceled)
- 6. (currently amended) A method for repairing line defects as described in claim 4, in which a shorting defect between [[a]] the scan line and the signal line is detected by applying a voltage between the scan line and the signal line and locating the source of then detecting an infrared signal being produced at the position of the shorting defect using an infrared detector heat produced at the short.
 - 7. (canceled)
 - 8. (withdrawn) A method for repairing line defects comprising steps for:

detecting a shorting defect between a scan line and signal line in a flat panel display unit wherein scan lines and signal lines are formed with an inter layer insulation film therebetween;

supplying insulation film material locally to an area containing a scan line where a shorting defect has occurred using the previously detected location of the shorting defect:

severing the scan line by emitting a laser beam through the insulation film material to the scan line with the shorting defect; and

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forming an insulation film locally at the part severed by emitting the laser beam to the scan line.

- 9. (withdrawn) A method for repairing line defects as described in claim 8, wherein either the scan line or signal line or both bifurcate where the scan line and signal line intersect with the interlayer insulation film therebetween.
- 10. (withdrawn) A method for repairing line defects as described in claim 8, wherein the insulation film is formed locally at the part cut be emitting a laser beam, by locally coating the cut part with an insulation film material and heat curing the coated insulation film material.
- 11. (withdrawn) A flat panel display unit having an interlayer insulation film, and a scan line and signal line disposed with an interlayer insulation film therebetween, either the scan line or signal line or both bifurcating where the scan line and signal line intersect and representing a shorting defect, wherein:

an insulating layer has been added to cover a region at the location of the shorting defect, and not to all of the rest of the display unit; and

part of one of the scan lines is severed at part of the bifurcation at an intersection with the signal line, and the severed part is coated with an insulation film.

- 12. (withdrawn) A flat panel display unit as described in claim 11, wherein the scan line and signal line are shorted near the severed part.
 - 13. (canceled)
 - 14. (canceled)
 - 15. (canceled)
- 16. (new) A method for repairing line defects as described in claim 1, further comprising forming an organic insulation film on to the repaired portion.